

<b>Notice of References Cited</b>	Application/Control No. 10/003,482	Applicant(s)/Patent Under Reexamination UR ET AL.	
	Examiner J. Derek Rutten	Art Unit 2192	Page 1 of 1

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	M	US-			

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	W	Geist et al., "Coverage-Directed Test Generation Using Symbolic Techniques", November 1996, Proceedings of the First International Conference on Formal Methods in Computer-Aided Design, Lecture Notes In Computer Science; Vol. 1166, ISBN:3-540-61937-2
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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.